

Notice of References Cited

Application/Control No.

10/607,830

Applicant(s)/Patent Under
Reexamination
BAKKE ET AL

Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,718,383	04-2004	Hebert, James E.	709/224
*	B	US-2002/0023150	02-2002	Osafune et al.	709/221
*	C	US-6,728,780	04-2004	Hebert, James E.	709/239
*	D	US-6,392,990	05-2002	Tosey et al.	370/218
*	E	US-6,560,630	05-2003	Vepa et al.	709/250
*	F	US-6,845,403	01-2005	Chadalapaka, Mallikarjun B	710/5
*	G	US-2003/0145108	07-2003	Joseph et al.	709/239
*	H	US-6,151,297	11-2000	Congdon et al.	370/216
*	I	US-5,935,215	08-1999	Bell et al.	709/239
*	J	US-6,885,633	04-2005	Mikkonen, Olli	370/220
*	K	US-6,874,147	03-2005	Diamant, Nimrod	709/220
*	L	US-6,665,702	12-2003	Zisapel et al.	709/238
*	M	US-6,938,092	08-2005	Burns, David A.	709/245

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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